



Photoelectric Detection Systems: Basics and Applications

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Deadline for manuscript
submissions:

closed (31 October 2022)

Message from the Guest Editor

Photoelectric detection is moving toward high performance, low cost, and small volume to meet rising demand and plays a very important role in a wide range of areas, including electro-optical displays, image sensing, environment monitoring, telecommunications, military uses, space exploration, security checks, and so on. Advances in photoelectric detection systems crucially depend upon a synergistic, multidisciplinary research effort. Recently, materials scientists, physicists, chemists, and engineers have reported much research on improving the key figure-of-merit parameters of photoelectric detection systems such as sensitivity, spectral selectivity, response speed, and stability.

In this Special Issue, authors can submit research and application studies devoted to photoelectric effects and various detectors. Additionally, papers about materials synthesis and the fabrication of photoelectric detectors will be accepted. Moreover, the modeling and simulation of photoelectric detectors is a crucial step that must be taken prior to application, and research papers in this area are also welcome in this Special Issue.





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Message from the Editor-in-Chief

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